Dr. A. D. Giddings (Devin)

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Dr. A. D. Giddings (Devin) is an Applications Scientist for CAMECA Instruments, a role in which he focuses on supporting the atom probe community in Asia. He has extensive experience with using APT in commercial environments around the world, having worked with the LEAP and EIKOS instruments in Toshiba, TSMC and branches of CAMECA in the USA, Japan and Korea, as well as with various universities and research institutes.

Devin is currently stationed in Korea, where his background in semiconductor physics and device metrology is invaluable in promoting the use of atom probe for the critical microelectronics industry. He has been pioneering nano-scale analysis of semiconductor devices, including logic, DRAM, NAND and GaN based materials. Before that, Devin was based in Japan where he was responsible for running customer demos on the EIKOS at the CAMECA-NIMS Atom Probe Lab. The EIKOS was applied to a diverse range of applications from Ag to ZnO, with a particular focus on metallic materials. Devin has experience establishing new atom probe facilities, having worked on the successful grant to create an atom probe centre in the Netherlands and then setting up and managing the LEAP at TSMC in Taiwan.

Devin has a bachelor's degree in mathematics & physics from the University of Warwick and a doctoral degree in semiconductor spintronics from the University of Nottingham. He is a member of the Institute of Physics (IOP) and a Fellow of the Royal Society of Arts, Manufactures and Commerce (RSA).